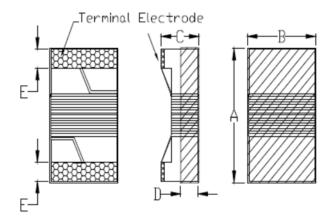


FEATRLRES

- Ferrite core wire wound construction.
- High Reliability due to wire wound type construction.
- Small footprint as well as low profile.
- Application for Signal Use.
- 100% Lead(Pb) & Halogen-Free and RoHS compliant.

CONFIGRLRATIONS & DIMENSIONS (unit in mm)



Size	Α	В	С	D	E
SWI0603	1.8max	1.2max	1.2max	0.38ref.	0.35±0.1

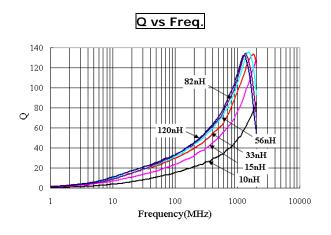
ELECTRICAL CHARACTERISTICS

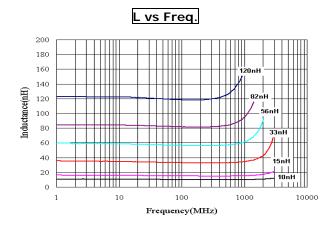
Part Number	Inductance (nH)	Tolerance	Test Frequency (Hz)	Q min.	Rated Current (mA) max	DCR (Ω) max.	SRF (MHz) min.
SWI0603F-2N0C	2.0±0.2nH	C,S	0.1V/250M	13	700	0.07	8000
SWI0603F-3N9C	3.9±0.2nH	C,S	0.1V/250M	22	700	0.07	6900
SWI0603F-4N7C	4.7±0.2nH	C,J,K	0.1V/250M	20	700	0.12	5800
SWI0603F-6N8C	6.8±0.2nH	C,J,K	0.1V/250M	27	700	0.08	5800
SWI0603F-8N2C	8.2±0.2nH	C,J,K	0.1V/250M	30	700	0.13	4200
SWI0603F-10NJ	10±5%	J,K	0.1V/250M	31	700	0.13	4800
SWI0603F-12NJ	12±5%	J,K	0.1V/250M	35	700	0.13	4000
SWI0603F-15NJ	15±5%	J,K	0.1V/250M	35	700	0.13	4000
SWI0603F-18NJ	18±5%	J,K	0.1V/250M	35	700	0.16	3100
SWI0603F-22NJ	22±5%	J,K	0.1V/250M	38	700	0.23	3000
SWI0603F-24NJ	24±5%	J,K	0.1V/250M	38	700	0.13	2800
SWI0603F-27NJ	27±5%	J,K	0.1V/250M	40	600	0.14	2800
SWI0603F-33NJ	33±5%	J,K	0.1V/250M	40	600	0.22	2300
SWI0603F-39NJ	39±5%	J.K	0.1V/250M	40	600	0.30	2200
SWI0603F-47NJ	47±5%	J,K	0.1V/200M	38	600	0.35	2000
SWI0603F-56NJ	56±5%	J,K	0.1V/200M	38	600	0.37	1900



SWI0603F-68NJ	68±5%	J,K	0.1V/200M	37	600	0.43	1700
SWI0603F-72NJ	72±5%	J,K	0.1V/150M	34	400	0.42	1700
SWI0603F-82NJ	82±5%	J,K	0.1V/150M	34	400	0.71	1700
SWI0603F-R10J	100±5%	J,K	0.1V/150M	34	400	0.78	1400
SWI0603F-R12J	120±5%	J,K	0.1V/150M	32	300	0.84	1300
SWI0603F-R15J	150±5%	J,K	0.1V/150M	28	280	0.96	990
SWI0603F-R18J	180±5%	J,K	0.1V/100M	25	240	1.52	990
SWI0603F-R22J	220±5%	J,K	0.1V/100M	25	200	2.02	900
SWI0603F-R27J	270±5%	J,K	0.1V/100M	24	170	2.36	900
SWI0603F-R33J	330±5%	J,K	0.1V/100M	24	185	3.40	700
SWI0603F-R39J	390±5%	J,K	0.1V/100M	24	100	3.60	900

- NOTE: Tolerance $C = \pm 0.2\%$, $S = \pm 0.3\%$, $G = \pm 2\%$, $J = \pm 5\%$, $K = \pm 10\%$
- Rated Current: 15° rise above 25° ambient.







Reliability and Test Condition

Item	Performance	Test Condition					
Operating temperature	-40~+125℃ (Including self - temperature rise)						
Storage temperature	110~+40°C,50~60%RH (Product with taping) 240~+125°C (on board)						
Electrical Performance Test							
Inductance		HP4284A,CH11025,CH3302,CH1320,CH1320S LCR Meter.					
DCR	Refer to standard electrical characteristics list.	CH16502,Agilent33420A Micro-Ohm Meter.					
Saturation Current (Isat)	Approximately∆L30%	Saturation DC Current (Isat) will cause L0 to drop △L(%)					
Heat Rated Current (Irms)	Approximately △T40°C	Heat Rated Current (Irms) will cause the coil temperature rise $\triangle T(C)$. 1.Applied the allowed DC current 2.Temperature measured by digital surface thermometer					
Reliability Test							
Life Test		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles) Temperature: 125±2°C (Inductor) Applied current: rated current Duration: 1000±12hrs Measured at room temperature after placing for 24±2 hrs					
Load Humidity		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Humidity: 85±2 * R.H, Temperature: 85°C±2°C Duration: 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24±2 hrs					
Moisture Resistance	Appearance: No damage. Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles 1. Baked at50°C for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs. 3. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs, keep at 25°C for 2 hrs then keep at -10°C for 3 hrs 4. Keep at 25°C 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.					
Thermal shock		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles Condition for 1 cycle Step1: -40±2°C 30±5min Step2: 25±2°C ≤0.5min Step3: 125±2°C 30±5min Number of cycles: 500 Measured at room temperature after placing for 24±2 hrs Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes					
Vibration		Equipment: Vibration checker Total Amplitude:1.52mm±10% Testing Time: 12 hours(20 minutes, 12 cycles each of 3 orientations).					
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805 inch(2012mm):40x100x1.2mm <0805 inch(2012mm):40x100x0.8mm Bending depth: >=0805 inch(2012mm):1.2mm <0805 inch(2012mm):0.8mm duration of 10 sec.					
Shock	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value	Type Peak value (g's) Normal duration (D) (ms) Wave form Velocity change (Vi)ft/sec SMD 50 11 Half-sine 11.3 Lead 50 11 Half-sine 11.3					
Solder ability	More than 95% of the terminal electrode should be covered with solder.	Preheat: 150°C,60sec. Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C ∘ Flux for lead free: Rosin. 9.5% ∘ Dip time: 4±1sec ∘					



		Depth: completely cover the termination				
		Depth: completely cover the termination				
Resistance to Soldering Heat		Temperature (°C) Time(s) Temperature ramp/immersion and emersion rate Number of heat cycles				
		260 ±5 (solder temp) 10 ±1 25mm/s ±6 mm/s 1				
Terminal Strength	Appearance: No damage. Impedance: within±15% of initial value Inductance: within±10% of initial value Q: Shall not exceed the specification value. RDC: within ±15% of initial value and shall not exceed the specification value e	Preconditioning: Run through IR reflow for 2 times. (IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force(>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested.				

Note: When there are questions concerning measurement result: measurement shall be made after 48 ± 2 hours of recovery under the standard condition.